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Mechanical strain engineering of dielectric tunability in polycrystalline $SrTiO_3$ thin films

By

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Supplementary information

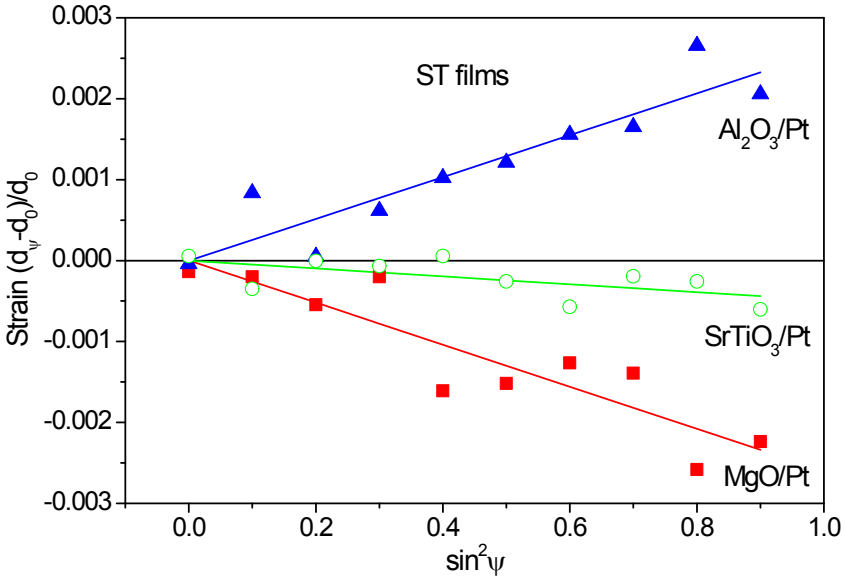


Figure S1. Strain $(d_\psi-d_0)/d_0$ of $SrTiO_3$ films deposited on Al_2O_3/Pt, $SrTiO_3$/Pt, and MgO/Pt substrates and their linear fits used for stress calculations.

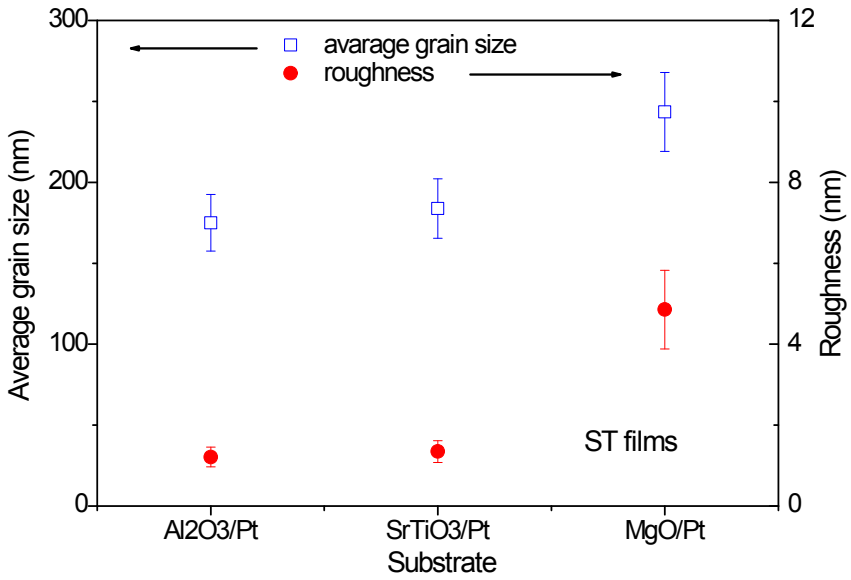
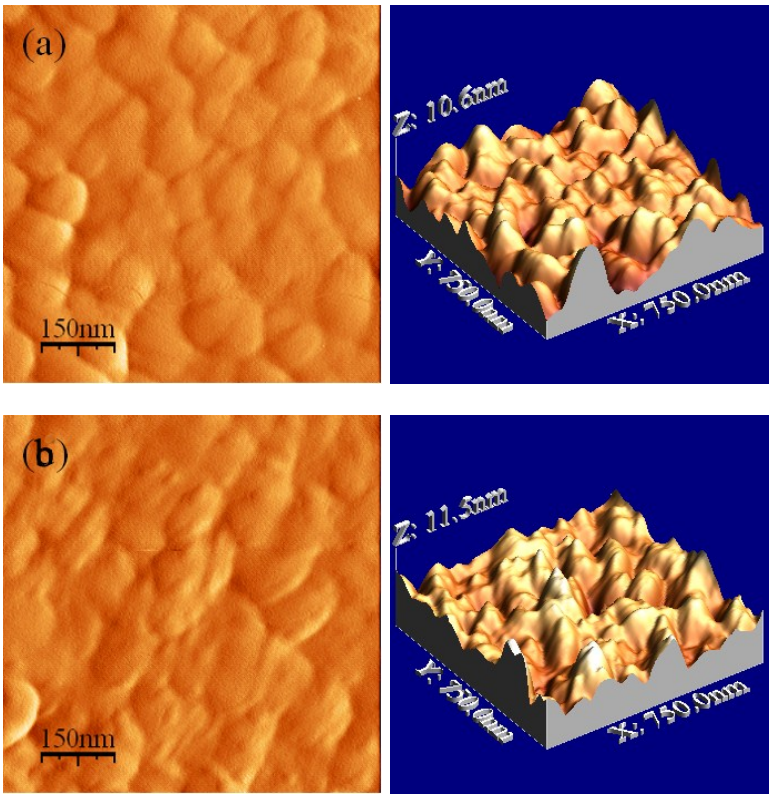


Figure S2. In-plane average grain size (*left axis*) and roughness (*right axis*) of $SrTiO_3$ films deposited on Al_2O_3/Pt, $SrTiO_3$/Pt (ST/Pt) and MgO/Pt substrates.



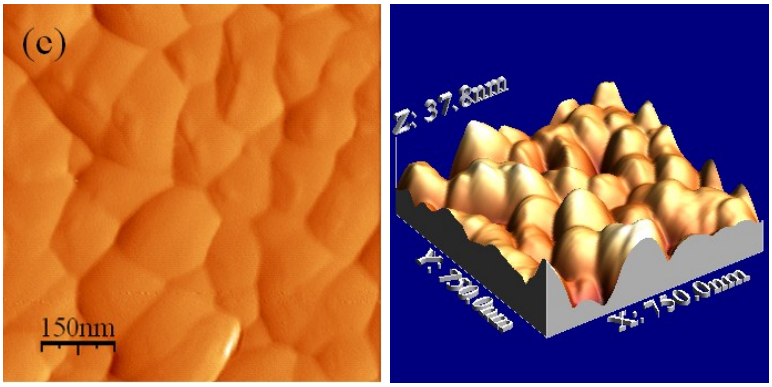


Figure S3. In-plane surface morphology (*left*) and the corresponding 3D views (*right*) of $SrTiO_3$ thin films deposited on Al_2O_3/Pt (a), $SrTiO_3$/Pt (b) and MgO/Pt (c) substrates obtained by atomic force microscopy.